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Cable	SMA-SMA
Case	240x185x50 mm
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Instructions

The probes from the XF1 set have electrically shielded probe heads which are designed for special magnetic field measurements on electronic assemblies, components and IC pins. The passive probes are connected to the 50 Ohm input of a spectrum analyser via SMA and allow comparative measurements of magnetic fields and disturbance currents in the frequency range from 30 MHz to 6 GHz.

NEAR FIELD PROBE SET XF 1

FREQUENCY RANGE 30 MHz to 6 GHz

Application	Description	Characteristic
	<p>RF-R 400 - 1 On account of its large diameter (25 mm) this magnetic field probe is the most sensitive in our range of products. It can be used at a distance of up to 10 cm from the units. The probe detects the spatial distribution of HF magnetic fields in devices and assemblies and allows the user to draw conclusions with regard to disturbance emissions.</p> <p>Frequency range: 30 MHz to 6 GHz Diameter approx. 25 mm</p>	
	<p>XF-R 3 - 1 The near field probe is designed for the detection of HF magnetic fields with a high geometrical resolution. The field orientation and distribution can be detected by moving the probe around conductor runs, bypass capacitors, EMC components and within IC pin and supply system areas.</p> <p>Frequency range: 30 MHz to 6 GHz Resolution approx. 1 mm</p>	
	<p>XF-B 3 - 1 The near field probe is designed for the detection of magnetic fields which are emitted vertically from the surface of PCBs and is thus ideal for investigating current loops. The probe allows the measurement in confined board areas (between large controller components, for example).</p> <p>Frequency range: 30 MHz to 6 GHz Diameter approx. 4 mm Resolution approx. 2 mm</p>	
	<p>XF-U 2.5 - 1 The near field probe is designed for the selective detection of RF currents in conductor runs, component connections, capacitors and IC pins. The probe head has a magnetically active curb with a width of approx. 0.5 mm. The probe's curb is positioned on conductor runs, ICs or capacitor connections for a measurement.</p> <p>Frequency range: 30 MHz to 6 GHz Resolution approx. 0.5 mm</p>	
	<p>XF-E 10 The near field probe detects electrical fields which are emitted from the surface of clocked leads. The probe head's tip is only 0.5 mm wide. Its integrated shielding prevents neighbouring leads from interfering with the measurement result. A resolution of approx. 0.2 mm is possible so that each individual conductor run can be evaluated in the layout.</p> <p>Frequency range: 30 MHz to 6 GHz Resolution approx. 0.1 mm conductor</p>	